# 2-Bit 20 Mb/s Dual-Supply Level Translator

The NLSX4373 is a 2-bit configurable dual-supply bidirectional auto sensing translator that does not require a directional control pin. The  $V_{CC}$  I/O and  $V_L$  I/O ports are designed to track two different power supply rails,  $V_{CC}$  and  $V_L$  respectively. The  $V_{CC}$  supply rail is configurable from 1.5 V to 5.5 V while  $V_L$  supply rail is configurable to 1.5 V to 5.5 V. This allows voltage logic signals on the  $V_L$  side to be translated into lower, higher or equal value voltage logic signals on the  $V_{CC}$  side, and vice–versa.

The NLSX4373 translator has open-drain outputs with integrated  $10~k\Omega$  pullup resistors on the I/O lines. The integrated pullup resistors are used to pullup the I/O lines to either  $V_L$  or  $V_{CC}.$  The NLSX4373 is an excellent match for open-drain applications such as the  $I^2C$  communication bus.

#### **Features**

- V<sub>L</sub> can be Less than, Greater than or Equal to V<sub>CC</sub>
- Wide V<sub>CC</sub> Operating Range: 1.5 V to 5.5 V
   Wide V<sub>L</sub> Operating Range: 1.5 V to 5.5 V
- High-Speed with 20 Mb/s Guaranteed Date Rate
- Low Bit-to-Bit Skew
- Enable Input and I/O Lines have Overvoltage Tolerant (OVT) to 5.5 V
- Nonpreferential Powerup Sequencing
- Integrated 10 kΩ Pullup Resistors
- Small packaging: UDFN8, SO-8, Micro8
- This is a Pb-Free Device

#### **Typical Applications**

- I<sup>2</sup>C, SMBus, PMBus
- Low Voltage ASIC Level Translation
- Mobile Phones, PDAs, Cameras

#### **Important Information**

- ESD Protection for All Pins
  - Human Body Model (HBM) > 7000 V



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#### MARKING DIAGRAMS



#### UDFN8 MU SUFFIX CASE 517AJ



VF = Specific Device Code

M = Date Code

= Pb-Free Package



#### SO-8 D SUFFIX CASE 751



A = Assembly Location

L = Wafer Lot
 Y = Year
 W = Work Week

= Pb-Free Package



1

#### Micro8 DM SUFFIX CASE 846A



A = Assembly Location

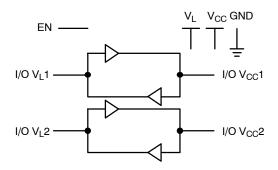
Y = Year
W = Work Week
= Pb-Free Package

#### ORDERING INFORMATION

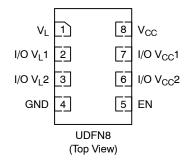
Device	Package	Shipping <sup>†</sup>
NLSX4373MUTAG	UDFN8 (Pb-Free)	3000/Tape & Reel
NLSX4373DR2G	SO-8 (Pb-Free)	2500/Tape & Reel
NLSX4373DMR2G	Micro8 (Pb-Free)	4000/Tape & Reel

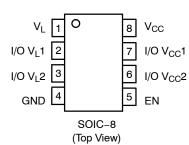
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

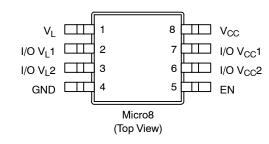
# LOGIC DIAGRAM



# **PIN ASSIGNMENTS**







# **PIN ASSIGNMENT**

Pins	Description
V <sub>CC</sub> V <sub>CC</sub> Input Voltage	
VL	V <sub>L</sub> Input Voltage
GND	Ground
EN Output Enable	
I/O V <sub>CC</sub> n V <sub>CC</sub> I/O Port, Referenced to V <sub>CC</sub>	
I/O V <sub>L</sub> n	V <sub>L</sub> I/O Port, Referenced to V <sub>L</sub>

# **FUNCTION TABLE**

EN	Operating Mode	
L	Hi–Z	
Н	I/O Buses Connected	

# **MAXIMUM RATINGS**

Symbol	Parameter	Value	Condition	Unit
V <sub>CC</sub>	High-side DC Supply Voltage	-0.3 to +7.0		V
V <sub>L</sub>	High-side DC Supply Voltage	-0.3 to +7.0		V
I/O V <sub>CC</sub>	V <sub>CC</sub> -Referenced DC Input/Output Voltage	-0.3 to (V <sub>CC</sub> + 0.3)		V
I/O V <sub>L</sub>	V <sub>L</sub> -Referenced DC Input/Output Voltage	-0.3 to (V <sub>L</sub> + 0.3)		V
V <sub>EN</sub>	Enable Control Pin DC Input Voltage	-0.3 to +7.0		V
I <sub>I/O_SC</sub>	Short-Circuit Duration (I/O V <sub>L</sub> and I/O V <sub>CC</sub> to GND)	40	Continuous	mA
T <sub>STG</sub>	Storage Temperature	-65 to +150		°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

# **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	V <sub>CC</sub> High-side Positive DC Supply Voltage		5.5	V
V <sub>L</sub>	High-side Positive DC Supply Voltage	1.5	5.5	V
V <sub>EN</sub>	Enable Control Pin Voltage	GND	5.5	V
V <sub>IO</sub>	Enable Control Pin Voltage	GND	5.5	V
T <sub>A</sub>	Operating Temperature Range	-40	+85	°C

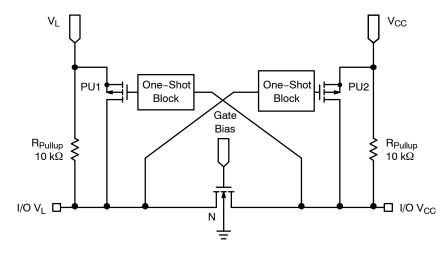


Figure 1. Block Diagram (1 I/O Line)

# **DC ELECTRICAL CHARACTERISTICS** ( $V_{CC}$ = 1.5 V to 5.5 V and $V_L$ = 1.5 V to 5.5 V, unless otherwise specified)

					С	
Symbol	Parameter	Test Conditions	Min	Typ (Notes 1, 2)	Max	Unit
V <sub>IHC</sub>	I/O V <sub>CC</sub> Input HIGH Voltage		V <sub>CC</sub> - 0.4	-	-	V
$V_{ILC}$	I/O V <sub>CC</sub> Input LOW Voltage		-	-	0.15	V
$V_{IHL}$	I/O V <sub>L</sub> Input HIGH Voltage		V <sub>L</sub> - 0.2	-	-	V
$V_{ILL}$	I/O V <sub>L</sub> Input LOW Voltage		-	-	0.15	V
$V_{IH}$	Control Pin Input HIGH Voltage		V <sub>L</sub> - 0.2	-	-	V
V <sub>IL</sub>	Control Pin Input LOW Voltage		-	-	0.15	V
V <sub>OHC</sub>	I/O V <sub>CC</sub> Output HIGH Voltage	I/O V <sub>CC</sub> Source Current = 20 μA	2/3 * V <sub>CC</sub>	-	-	V
V <sub>OLC</sub>	I/O V <sub>CC</sub> Output LOW Voltage	I/O V <sub>CC</sub> Sink Current = 20 μA	-	-	1/3 * V <sub>CC</sub>	V
$V_{OHL}$	I/O V <sub>L</sub> Output HIGH Voltage	I/O V <sub>L</sub> Source Current = 20 μA	2/3 * V <sub>L</sub>	-	-	V
V <sub>OLL</sub>	I/O V <sub>L</sub> Output LOW Voltage	I/O V <sub>L</sub> Sink Current = 20 μA	-	-	1/3 * V <sub>L</sub>	V
I <sub>QVCC</sub>	V <sub>CC</sub> Supply Current	I/O $V_{CC}$ and I/O $V_L$ Unconnected, $V_{EN} = V_L$	-	0.5	2.0	μΑ
$I_{QVL}$	V <sub>L</sub> Supply Current	I/O $V_{CC}$ and I/O $V_{L}$ Unconnected, $V_{EN} = V_{L}$	_	0.3	1.5	μΑ
I <sub>TS-VCC</sub>	V <sub>CC</sub> Tristate Output Mode Supply Current	I/O $V_{CC}$ and I/O $V_{L}$ Unconnected, $V_{EN}$ = GND	-	0.1	1.0	μΑ
I <sub>TS-VL</sub>	V <sub>L</sub> Tristate Output Mode Supply Current	I/O $V_{CC}$ and I/O $V_L$ Unconnected, $V_{EN} = \mbox{GND}$	-	0.1	1.0	μΑ
l <sub>OZ</sub>	I/O Tristate Output Mode Leakage Current	$T_A = +25^{\circ}C$	-	0.1	1.0	μΑ
R <sub>PU</sub>	Pullup Resistor I/O V <sub>L</sub> and V <sub>CC</sub>	$T_A = +25^{\circ}C$	-	10	-	kΩ

Typical values are for V<sub>CC</sub> = +2.8 V, V<sub>L</sub> = +1.8 V and T<sub>A</sub> = +25°C.
 All units are production tested at T<sub>A</sub> = +25°C. Limits over the operating temperature range are guaranteed by design.

# TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 2 and 3,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1  $M\Omega$ )

				0°C to +8 otes 3 and		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>L</sub> = 1.5 V, \	/ <sub>CC</sub> = 5.5 V					
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				20	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				30	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				20	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				20	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				5	nS
	Maximum Data Rate		20			Mb/s
V <sub>L</sub> = 1.8 V, \	/ <sub>CC</sub> = 2.8 V		•		•	•
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				15	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				25	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				5	nS
	Maximum Data Rate		20			Mb/s
V <sub>L</sub> = 2.5 V, \	/ <sub>CC</sub> = 3.6 V		•		•	•
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				10	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15	ns
tppskew	Part-to-Part Skew				5	nS
	Maximum Data Rate		20			Mb/s
V <sub>L</sub> = 2.8 V, \	/ <sub>CC</sub> = 1.8 V				•	•
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				25	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				20	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				15	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				5	nS
	Maximum Data Rate		20		1	Mb/s

<sup>3.</sup> Typical values are for  $V_{CC}$  = +3.3 V,  $V_L$  = +1.8 V and  $T_A$  = +25°C. 4. All units are production tested at  $T_A$  = +25°C. Limits over the operating temperature range are guaranteed by design.

# TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 2 and 3,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			-40°C to +85°C (Notes 3 and 4)			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>L</sub> = 3.6 V, \	/ <sub>CC</sub> = 2.5 V	<u>.</u>				•
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				15	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				15	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				15	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				5	nS
	Maximum Data Rate		20			Mb/s
V <sub>L</sub> = 5.5 V, \	/ <sub>CC</sub> = 1.5 V	<u>.</u>				•
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				30	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				20	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				20	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				20	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				5	nS
	Maximum Data Rate		20			Mb/s

<sup>3.</sup> Typical values are for  $V_{CC}$  = +3.3 V,  $V_L$  = +1.8 V and  $T_A$  = +25°C.

# TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS

(I/O test circuit of Figures 4 and 5,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			-40°C to +85°C (Notes 5 and 6) Min Typ Max			
Symbol	Parameter	Test Conditions			Unit	
+1.5 ≤ V <sub>L</sub> ≤	$+1.5 \le V_L \le V_{CC} \le +5.5 \text{ V}$					
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Risetime				400	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Falltime				50	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Risetime				400	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Falltime				60	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O V <sub>L</sub> )				1000	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O V <sub>CC</sub> )				1000	ns
tppskew	Part-to-Part Skew				50	nS
MDR	Maximum Data Rate		2			Mb/s

<sup>4.</sup> All units are production tested at  $T_A = +25$ °C. Limits over the operating temperature range are guaranteed by design.

<sup>5.</sup> Typical values are for V<sub>CC</sub> = +3.3 V, V<sub>L</sub> = +1.8 V and T<sub>A</sub> = +25°C.
6. All units are production tested at T<sub>A</sub> = +25°C. Limits over the operating temperature range are guaranteed by design.

# **TEST SETUPS**

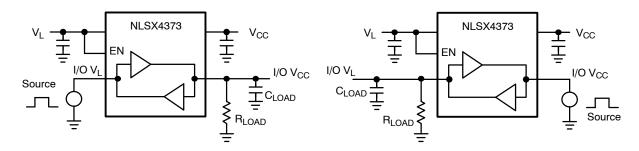


Figure 2. Rail-to-Rail Driving I/O V<sub>L</sub>

Figure 3. Rail-to-Rail Driving I/O V<sub>CC</sub>

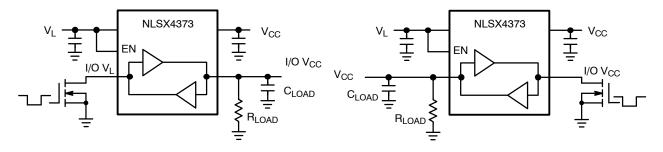


Figure 4. Open-Drain Driving I/O V<sub>L</sub>

Figure 5. Open-Drain Driving I/O  $V_{CC}$ 

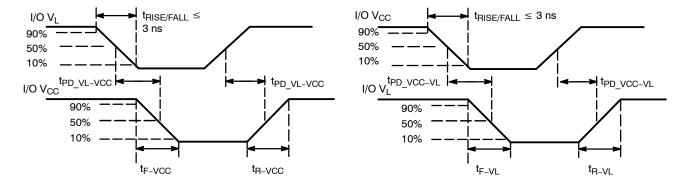
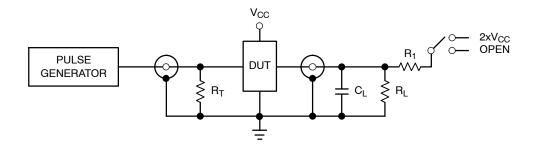


Figure 6. Definition of Timing Specification Parameters



Test	Switch
t <sub>PZH</sub> , t <sub>PHZ</sub>	Open
t <sub>PZL</sub> , t <sub>PLZ</sub>	2 x V <sub>CC</sub>

 $C_L$  = 15 pF or equivalent (Includes jig and probe capacitance)  $R_L$  =  $R_1$  = 50 k $\Omega$  or equivalent  $R_T$  =  $Z_{OUT}$  of pulse generator (typically 50  $\Omega$ )

Figure 7. Test Circuit for Enable/Disable Time Measurement

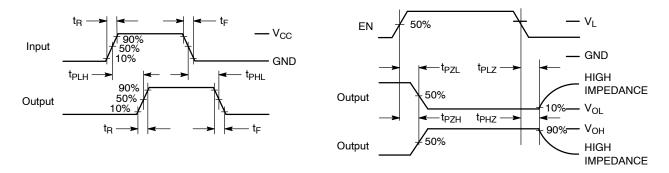


Figure 8. Timing Definitions for Propagation Delays and Enable/Disable Measurement

#### **APPLICATIONS INFORMATION**

#### **Level Translator Architecture**

The NLSX4373 auto sense translator provides bi–directional voltage level shifting to transfer data in multiple supply voltage systems. This device has two supply voltages,  $V_L$  and  $V_{CC}$ , which set the logic levels on the input and output sides of the translator. When used to transfer data from the  $V_L$  to the  $V_{CC}$  ports, input signals referenced to the  $V_L$  supply are translated to output signals with a logic level matched to  $V_{CC}$ . In a similar manner, the  $V_{CC}$  to  $V_L$  translation shifts input signals with a logic level compatible to  $V_{CC}$  to an output signal matched to  $V_L$ .

The NLSX4373 consists of two bi-directional channels that independently determine the direction of the data flow without requiring a directional pin. The one-shot circuits are used to detect the rising or falling input signals. In addition, the one shots decrease the rise and fall time of the output signal for high-to-low and low-to-high transitions.

Each input/output channel has an internal 10 k $\Omega$  pull. The magnitude of the pullup resistors can be reduced by connecting external resistors in parallel to the internal 10 k $\Omega$  resistors.

#### **Input Driver Requirements**

The rise (t<sub>R</sub>) and fall (t<sub>F</sub>) timing parameters of the open drain outputs depend on the magnitude of the pull-up resistors. In addition, the propagation times (t<sub>PD</sub>), skew (t<sub>PSKEW</sub>) and maximum data rate depend on the impedance of the device that is connected to the translator. The timing

parameters listed in the data sheet assume that the output impedance of the drivers connected to the translator is less than  $50~k\Omega$ .

#### **Enable Input (EN)**

The NLSX4373 has an Enable pin (EN) that provides tri–state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O  $V_{\rm CC}$  and I/O  $V_{\rm L}$  pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the  $V_{\rm L}$  supply and has Overvoltage Tolerant (OVT) protection.

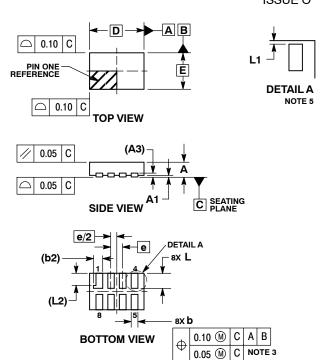
#### **Power Supply Guidelines**

During normal operation, supply voltage  $V_L$  can be greater than, less than or equal to  $V_{CC}$ . The sequencing of the power supplies will not damage the device during the power up operation.

For optimal performance, 0.01  $\mu F$  to 0.1  $\mu F$  decoupling capacitors should be used on the  $V_L$  and  $V_{CC}$  power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

#### PACKAGE DIMENSIONS

#### **UDFN8 1.8 x 1.2, 0.4P** CASE 517AJ-01 ISSUE O



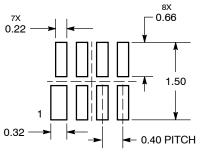
#### NOTES:

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30 mm FROM TERMINAL TIP.
  4. MOLD FLASH ALLOWED ON TERMINALS ALONG EDGE OF PACKAGE. FLASH MAY NOT EXCEED 0.30 ONTO BOTTOM SURFACE OF TERMINALS.
  5. DETAIL A SHOWS OPTIONAL CONSTRUCTION FOR TERMINALS.

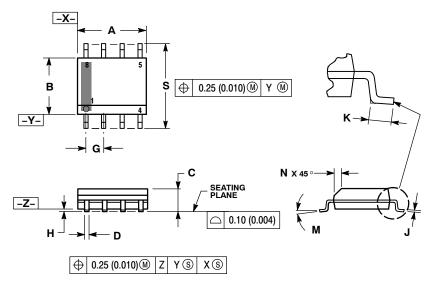
	MILLIMETERS				
DIM	MIN MAX				
Α	0.45 0.55				
A1	0.00 0.05				
A3	0.127 REF				
b	0.15 0.25				
b2	0.30	REF			
D	1.80	BSC			
E	1.20	BSC			
е	0.40	BSC			
L	0.45	0.55			
L1					
L2	0.40	REF			

#### **MOUNTING FOOTPRINT SOLDERMASK DEFINED**



#### **PACKAGE DIMENSIONS**

SO-8 CASE 751-07 **ISSUE AJ** 



#### NOTES:

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2. CONTROLLING DIMENSION: MILLIMETER.

  3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.

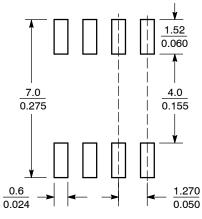
  4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- PER SIDE.

  5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

  6. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.05	0 BSC
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 ° 8	
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

# **SOLDERING FOOTPRINT\***

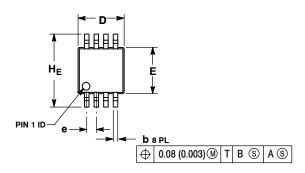


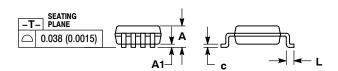
(mm inches SCALE 6:1

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

#### Micro8™ CASE 846A-02 **ISSUE H**



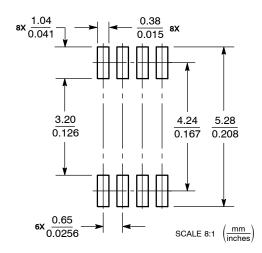


- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
  DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
- U.19 (U.UUG) PER SIDE.
  DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION.
  INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER

5. 846A-01 OBSOLETE, NEW STANDARD 846A-02

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α			1.10			0.043
A1	0.05	0.08	0.15	0.002	0.003	0.006
b	0.25	0.33	0.40	0.010	0.013	0.016
С	0.13	0.18	0.23	0.005	0.007	0.009
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
е	0.65 BSC			0.026 BSC		
L	0.40	0.55	0.70	0.016	0.021	0.028
HE	4.75	4.90	5.05	0.187	0.193	0.199

#### SOLDERING FOOTPRINT\*



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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